

NX3L4051-Q100

Single low-ohmic 8-channel analog switch

Rev. 1 — 7 August 2012

Product data sheet

1. General description

The NX3L4051-Q100 is a low-ohmic 8-channel analog switch, suitable for use as an analog or digital multiplexer/demultiplexer. The NX3L4051-Q100 has three digital select inputs (S1 to S3), eight independent inputs/outputs (Y0 to Y7) and a common input/output (Z). All eight switches share an enable input ($\bar{E}$). A HIGH on $\bar{E}$ causes all switches into the high impedance OFF-state, independent of Sn.

Schmitt trigger action at the digital inputs makes the circuit tolerant to slower input rise and fall times. Low threshold digital inputs allows this device to be driven by 1.8 V logic levels in 3.3 V applications without significant increase in supply current I_{CC} . This makes it possible for the NX3L4051-Q100 to switch 4.3 V signals with a 1.8 V digital controller, eliminating the need for logic level translation. The NX3L4051-Q100 allows signals with amplitude up to V_{CC} to be transmitted from Z to Yn or from Yn to Z. The low ON resistance (0.5 Ω) and flatness (0.13 Ω), ensures minimal attenuation and distortion of transmitted signals.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

2. Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
 - ◆ Specified from $-40\text{ }^{\circ}\text{C}$ to $+85\text{ }^{\circ}\text{C}$ and from $-40\text{ }^{\circ}\text{C}$ to $+125\text{ }^{\circ}\text{C}$
- Wide supply voltage range from 1.4 V to 4.3 V
- Very low ON resistance (peak):
 - ◆ 1.7 Ω (typical) at $V_{CC} = 1.4\text{ V}$
 - ◆ 1.0 Ω (typical) at $V_{CC} = 1.65\text{ V}$
 - ◆ 0.6 Ω (typical) at $V_{CC} = 2.3\text{ V}$
 - ◆ 0.5 Ω (typical) at $V_{CC} = 2.7\text{ V}$
 - ◆ 0.5 Ω (typical) at $V_{CC} = 4.3\text{ V}$
- Break-before-make switching
- High noise immunity
- ESD protection:
 - ◆ MIL-STD-883, method 3015 Class 3A exceeds 7500 V
 - ◆ HBM JESD22-A114F Class 3A exceeds 7500 V
 - ◆ MM JESD22-A115-A exceeds 200 V ($C = 200\text{ pF}$, $R = 0\text{ }\Omega$)
 - ◆ CDM AEC-Q100-011 revision B exceeds 1000 V
 - ◆ IEC61000-4-2 contact discharge exceeds 8000 V for switch ports
- CMOS low-power consumption



- Latch-up performance exceeds 100 mA per JESD 78B Class II Level A
- 1.8 V control logic at $V_{CC} = 3.6$ V
- Control input accepts voltages above supply voltage
- Very low supply current, even when input is below V_{CC}
- High current handling capability (350 mA continuous current under 3.3 V supply)

3. Applications

- Cell phone
- PDA
- Portable media player
- Analog multiplexing and demultiplexing
- Digital multiplexing and demultiplexing
- Signal gating

4. Ordering information

Table 1. Ordering information

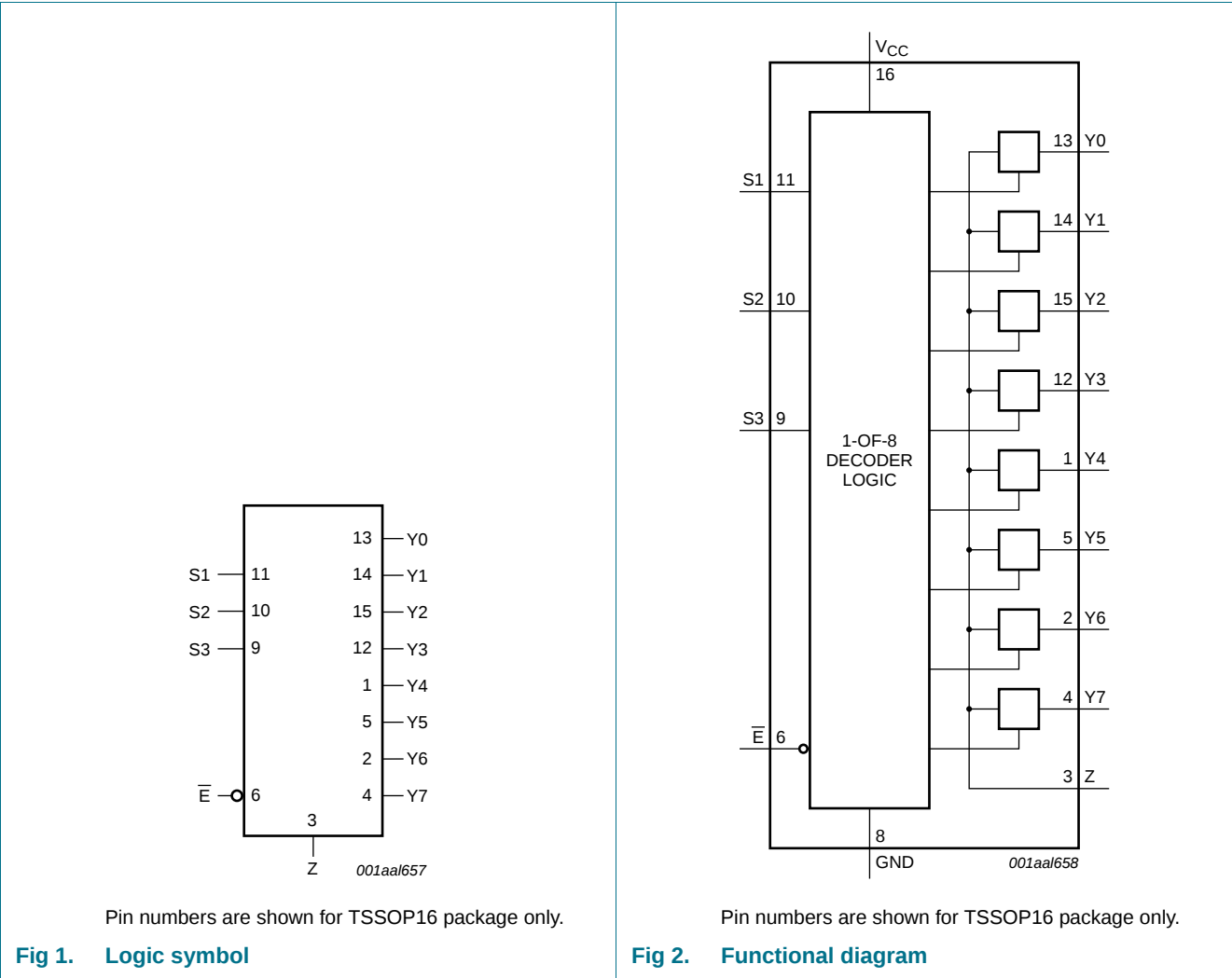
Type number	Package			
	Temperature range	Name	Description	Version
NX3L4051HR-Q100	-40 °C to +125 °C	HXQFN16	plastic thermal enhanced extremely thin quad flat package; no leads; 16 terminals; body 3 × 3 × 0.5 mm	SOT1039-2
NX3L4051PW-Q100	-40 °C to +125 °C	TSSOP16	plastic thin shrink small outline package; 16 leads; body width 4.4 mm	SOT403-1

5. Marking

Table 2. Marking codes

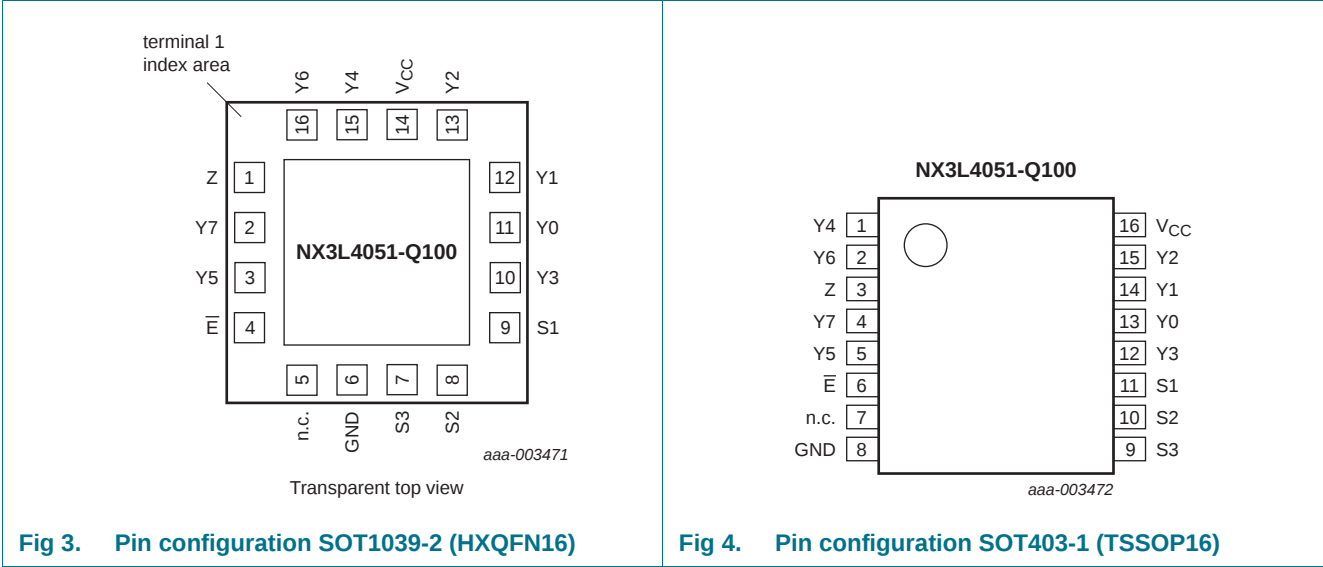
Type number	Marking code
NX3L4051HR-Q100	M41
NX3L4051PW-Q100	X3L4051

6. Functional diagram



7. Pinning information

7.1 Pinning



7.2 Pin description

Table 3. Pin description

Symbol	Pin		Description
	SOT1039-2	SOT403-1	
Y0, Y1, Y2, Y3, Y4, Y5, Y6, Y7	11, 12, 13, 10, 15, 3, 16, 2	13, 14, 15, 12, 1, 5, 2, 4	independent input or output
Z	1	3	independent output or input
$\overline{E}$	4	6	enable input (active LOW)
n.c.	5	7	not connected
GND	6	8	ground (0 V)
S1, S2, S3	9, 8, 7	11, 10, 9	select input
V _{CC}	14	16	supply voltage

8. Functional description

Table 4. Function table^[1]

Input				Channel ON
$\bar{E}$	S3	S2	S1	
L	L	L	L	Y0 = Z
L	L	L	H	Y1 = Z
L	L	H	L	Y2 = Z
L	L	H	H	Y3 = Z
L	H	L	L	Y4 = Z
L	H	L	H	Y5 = Z
L	H	H	L	Y6 = Z
L	H	H	H	Y7 = Z
H	X	X	X	switches off

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care.

9. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+4.6	V
V_I	input voltage	S_n and $\bar{E}$	^[1] -0.5	+4.6	V
V_{SW}	switch voltage		^[2] -0.5	$V_{CC} + 0.5$	V
I_{IK}	input clamping current	$V_I < -0.5$ V	-50	-	mA
I_{SK}	switch clamping current	$V_I < -0.5$ V or $V_I > V_{CC} + 0.5$ V	-	±50	mA
I_{SW}	switch current	$V_{SW} > -0.5$ V or $V_{SW} < V_{CC} + 0.5$ V; source or sink current	-	±350	mA
		$V_{SW} > -0.5$ V or $V_{SW} < V_{CC} + 0.5$ V; pulsed at 1 ms duration, < 10 % duty cycle; peak current	-	±500	mA
T_{stg}	storage temperature		-65	+150	°C
P_{tot}	total power dissipation	$T_{amb} = -40$ °C to +125 °C			
		HXQFN16	^[3] -	250	mW
		TSSOP16	^[4] -	500	mW

[1] The minimum input voltage rating may be exceeded if the input current rating is observed.

[2] The minimum and maximum switch voltage ratings may be exceeded if the switch clamping current rating is observed but may not exceed 4.6 V.

[3] For HXQFN16 package: above 135 °C the value of P_{tot} derates linearly with 16.9 mW/K.

[4] For TSSOP16 package: above 60 °C the value of P_{tot} derates linearly with 5.5 mW/K.

10. Recommended operating conditions

Table 6. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		1.4	4.3	V
V_I	input voltage	Sn and $\bar{E}$	0	4.3	V
V_{SW}	switch voltage		1 0	V_{CC}	V
T_{amb}	ambient temperature		-40	+125	°C
$\Delta t/\Delta V$	input transition rise and fall rate	Sn and $\bar{E}$; $V_{CC} = 1.4\text{ V to }4.3\text{ V}$	-	200	ns/V

- [1] To avoid sinking GND current from terminal Z when switch current flows in terminal Yn, the voltage drop across the bidirectional switch must not exceed 0.4 V. If the switch current flows into terminal Z, no GND current flows from terminal Yn. In this case, there is no limit for the voltage drop across the switch.

11. Static characteristics

Table 7. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground 0 V).

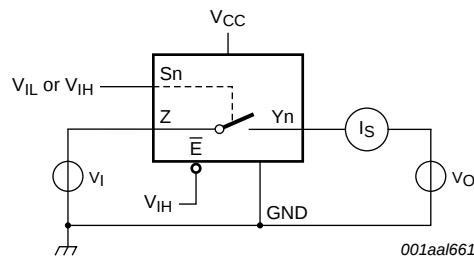
Symbol	Parameter	Conditions	$T_{amb} = 25\text{ °C}$			$T_{amb} = -40\text{ °C to }+125\text{ °C}$			Unit
			Min	Typ	Max	Min	Max (85 °C)	Max (125 °C)	
V_{IH}	HIGH-level input voltage	$V_{CC} = 1.4\text{ V to }1.6\text{ V}$	0.9	-	-	0.9	-	-	V
		$V_{CC} = 1.65\text{ V to }1.95\text{ V}$	0.9	-	-	0.9	-	-	V
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$	1.1	-	-	1.1	-	-	V
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$	1.3	-	-	1.3	-	-	V
		$V_{CC} = 3.6\text{ V to }4.3\text{ V}$	1.4	-	-	1.4	-	-	V
V_{IL}	LOW-level input voltage	$V_{CC} = 1.4\text{ V to }1.6\text{ V}$	-	-	0.3	-	0.3	0.3	V
		$V_{CC} = 1.65\text{ V to }1.95\text{ V}$	-	-	0.4	-	0.4	0.3	V
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$	-	-	0.4	-	0.4	0.4	V
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$	-	-	0.5	-	0.5	0.5	V
		$V_{CC} = 3.6\text{ V to }4.3\text{ V}$	-	-	0.6	-	0.6	0.6	V
I_I	input leakage current	Sn and $\bar{E}$; $V_I = \text{GND to }4.3\text{ V}$; $V_{CC} = 1.4\text{ V to }4.3\text{ V}$	-	-	-	-	± 0.5	± 1	μA
$I_{S(OFF)}$	OFF-state leakage current	Yn ports; see Figure 5							
		$V_{CC} = 1.4\text{ V to }3.6\text{ V}$	-	-	± 5	-	± 50	± 500	nA
		$V_{CC} = 3.6\text{ V to }4.3\text{ V}$	-	-	± 10	-	± 50	± 500	nA
$I_{S(ON)}$	ON-state leakage current	Z port; $V_{CC} = 1.4\text{ V to }3.6\text{ V}$; see Figure 6							
		$V_{CC} = 1.4\text{ V to }3.6\text{ V}$	-	-	± 20	-	± 200	± 2000	nA
		$V_{CC} = 3.6\text{ V to }4.3\text{ V}$	-	-	± 40	-	± 200	± 2000	nA
I_{CC}	supply current	$V_I = V_{CC}\text{ or GND}$; $V_{SW} = \text{GND or }V_{CC}$							
		$V_{CC} = 3.6\text{ V}$	-	-	100	-	500	5000	nA
		$V_{CC} = 4.3\text{ V}$	-	-	150	-	800	6000	nA

Table 7. Static characteristics ...continued

At recommended operating conditions; voltages are referenced to GND (ground 0 V).

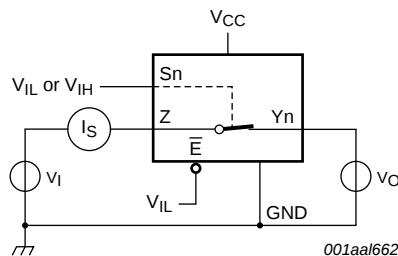
Symbol	Parameter	Conditions	T _{amb} = 25 °C			T _{amb} = –40 °C to +125 °C			Unit
			Min	Typ	Max	Min	Max (85 °C)	Max (125 °C)	
ΔI _{CC}	additional supply current	V _{SW} = GND or V _{CC}							
		V _I = 2.6 V; V _{CC} = 4.3 V	-	2.0	4.0	-	7	7	μA
		V _I = 2.6 V; V _{CC} = 3.6 V	-	0.35	0.7	-	1	1	μA
		V _I = 1.8 V; V _{CC} = 4.3 V	-	7.0	10.0	-	15	15	μA
		V _I = 1.8 V; V _{CC} = 3.6 V	-	2.5	4.0	-	5	5	μA
		V _I = 1.8 V; V _{CC} = 2.5 V	-	50	200	-	300	500	nA
C _I	input capacitance	S _n and $\bar{E}$	-	1.0	-	-	-	-	pF
C _{S(OFF)}	OFF-state capacitance		-	35	-	-	-	-	pF
C _{S(ON)}	ON-state capacitance		-	350	-	-	-	-	pF

11.1 Test circuits



V_I = 0.3 V or V_{CC} – 0.3 V; V_O = V_{CC} – 0.3 V or 0.3 V.

Fig 5. Test circuit for measuring OFF-state leakage current



V_I = 0.3 V or V_{CC} – 0.3 V; V_O = V_{CC} – 0.3 V or 0.3 V.

Fig 6. Test circuit for measuring ON-state leakage current

11.2 ON resistance

Table 8. ON resistance^[1]

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); for graphs see [Figure 8](#) to [Figure 14](#).

Symbol	Parameter	Conditions	T _{amb} = –40 °C to +85 °C			T _{amb} = –40 °C to +125 °C		Unit
			Min	Typ ^[2]	Max	Min	Max	
R _{ON(peak)}	ON resistance (peak)	V _I = GND to V _{CC} ; I _{SW} = 100 mA; see Figure 7						
		V _{CC} = 1.4 V	-	1.7	3.7	-	4.1	Ω
		V _{CC} = 1.65 V	-	1.0	1.6	-	1.7	Ω
		V _{CC} = 2.3 V	-	0.6	0.8	-	0.9	Ω
		V _{CC} = 2.7 V	-	0.5	0.75	-	0.9	Ω
		V _{CC} = 4.3 V	-	0.5	0.75	-	0.9	Ω
ΔR _{ON}	ON resistance mismatch between channels	V _I = GND to V _{CC} ; I _{SW} = 100 mA [3]						
		V _{CC} = 1.4 V; V _{SW} = 0.4 V	-	0.18	0.30	-	0.30	Ω
		V _{CC} = 1.65 V; V _{SW} = 0.5 V	-	0.18	0.20	-	0.30	Ω
		V _{CC} = 2.3 V; V _{SW} = 0.7 V	-	0.07	0.10	-	0.13	Ω
		V _{CC} = 2.7 V; V _{SW} = 0.8 V	-	0.07	0.10	-	0.13	Ω
		V _{CC} = 4.3 V; V _{SW} = 0.8 V	-	0.07	0.10	-	0.13	Ω
R _{ON(flat)}	ON resistance (flatness)	V _I = GND to V _{CC} ; I _{SW} = 100 mA [4]						
		V _{CC} = 1.4 V	-	1.0	3.3	-	3.6	Ω
		V _{CC} = 1.65 V	-	0.5	1.2	-	1.3	Ω
		V _{CC} = 2.3 V	-	0.15	0.3	-	0.35	Ω
		V _{CC} = 2.7 V	-	0.13	0.3	-	0.35	Ω
		V _{CC} = 4.3 V	-	0.2	0.4	-	0.45	Ω

[1] For NX3L4051PW-Q100 (TSSOP16 package), all ON resistance values are up to 0.05 Ω higher.

[2] Typical values are measured at T_{amb} = 25 °C.

[3] Measured at identical V_{CC}, temperature and input voltage.

[4] Flatness is defined as the difference between the maximum and minimum value of ON resistance measured at identical V_{CC} and temperature.

11.3 ON resistance test circuit and graphs

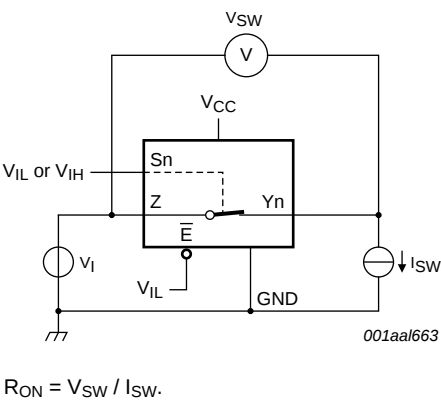
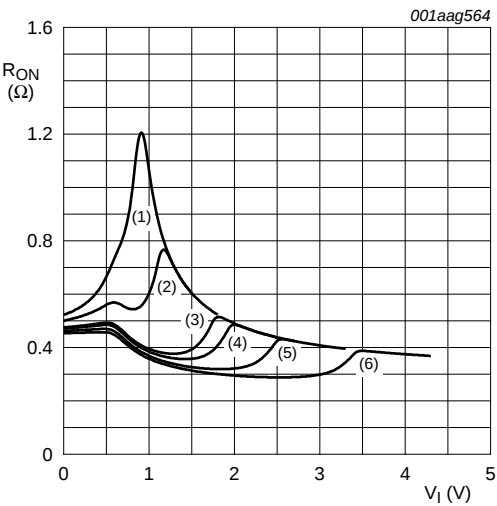
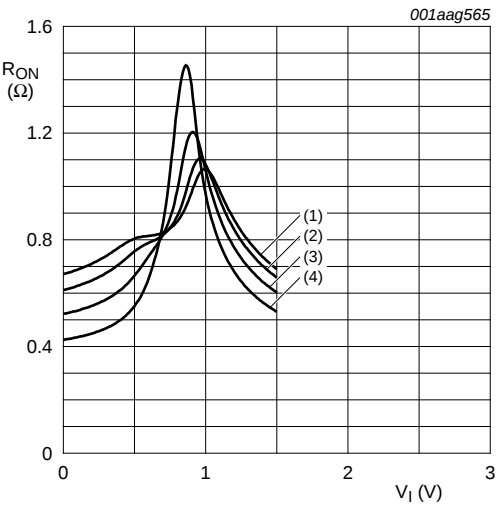


Fig 7. Test circuit for measuring ON resistance



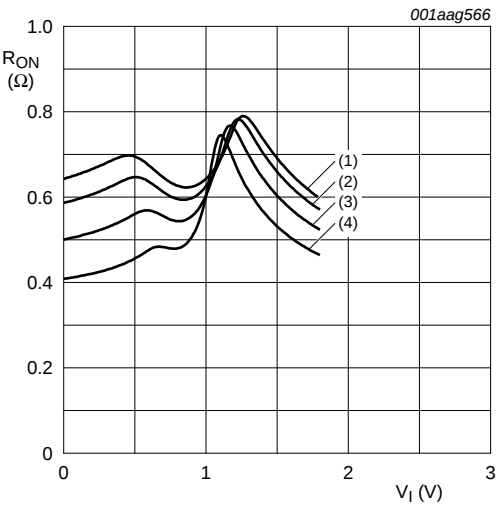
- (1) $V_{CC} = 1.5\text{ V}$.
 - (2) $V_{CC} = 1.8\text{ V}$.
 - (3) $V_{CC} = 2.5\text{ V}$.
 - (4) $V_{CC} = 2.7\text{ V}$.
 - (5) $V_{CC} = 3.3\text{ V}$.
 - (6) $V_{CC} = 4.3\text{ V}$.
- Measured at $T_{amb} = 25\text{ }^{\circ}\text{C}$.

Fig 8. Typical ON resistance as a function of input voltage



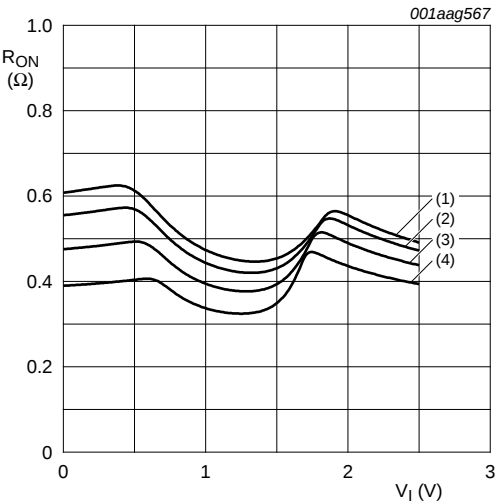
- (1) $T_{amb} = 125\text{ }^{\circ}\text{C}.$
- (2) $T_{amb} = 85\text{ }^{\circ}\text{C}.$
- (3) $T_{amb} = 25\text{ }^{\circ}\text{C}.$
- (4) $T_{amb} = -40\text{ }^{\circ}\text{C}.$

Fig 9. ON resistance as a function of input voltage;
 $V_{CC} = 1.5\text{ V}$



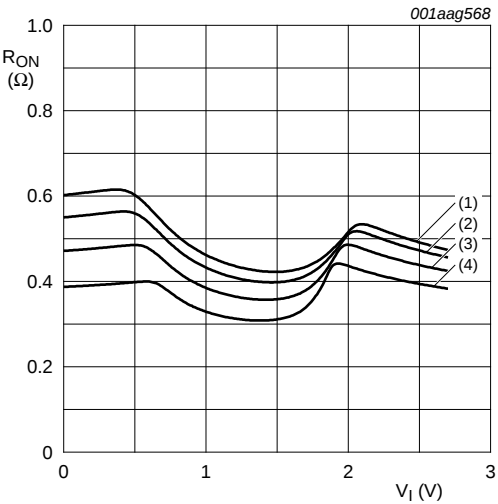
- (1) $T_{amb} = 125\text{ }^{\circ}\text{C}.$
- (2) $T_{amb} = 85\text{ }^{\circ}\text{C}.$
- (3) $T_{amb} = 25\text{ }^{\circ}\text{C}.$
- (4) $T_{amb} = -40\text{ }^{\circ}\text{C}.$

Fig 10. ON resistance as a function of input voltage;
 $V_{CC} = 1.8\text{ V}$



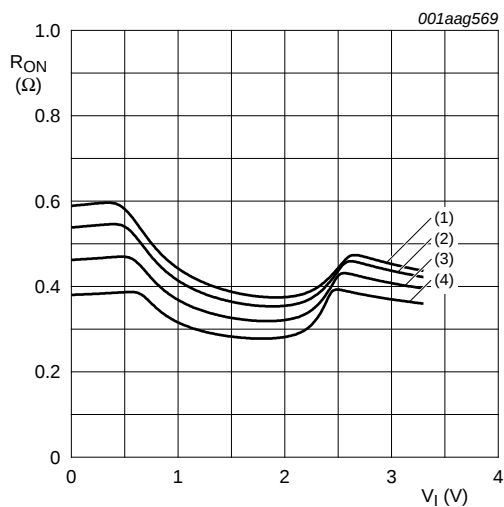
- (1) $T_{amb} = 125\text{ }^{\circ}\text{C}.$
- (2) $T_{amb} = 85\text{ }^{\circ}\text{C}.$
- (3) $T_{amb} = 25\text{ }^{\circ}\text{C}.$
- (4) $T_{amb} = -40\text{ }^{\circ}\text{C}.$

Fig 11. ON resistance as a function of input voltage;
 $V_{CC} = 2.5\text{ V}$



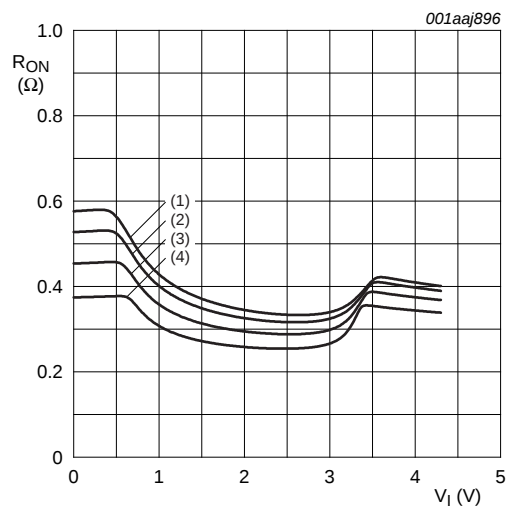
- (1) $T_{amb} = 125\text{ }^{\circ}\text{C}.$
- (2) $T_{amb} = 85\text{ }^{\circ}\text{C}.$
- (3) $T_{amb} = 25\text{ }^{\circ}\text{C}.$
- (4) $T_{amb} = -40\text{ }^{\circ}\text{C}.$

Fig 12. ON resistance as a function of input voltage;
 $V_{CC} = 2.7\text{ V}$



- (1) $T_{amb} = 125\text{ °C}$.
- (2) $T_{amb} = 85\text{ °C}$.
- (3) $T_{amb} = 25\text{ °C}$.
- (4) $T_{amb} = -40\text{ °C}$.

Fig 13. ON resistance as a function of input voltage;
 $V_{CC} = 3.3\text{ V}$



- (1) $T_{amb} = 125\text{ °C}$.
- (2) $T_{amb} = 85\text{ °C}$.
- (3) $T_{amb} = 25\text{ °C}$.
- (4) $T_{amb} = -40\text{ °C}$.

Fig 14. ON resistance as a function of input voltage;
 $V_{CC} = 4.3\text{ V}$

12. Dynamic characteristics

Table 9. Dynamic characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); for load circuit see [Figure 17](#).

Symbol	Parameter	Conditions	$T_{amb} = 25\text{ °C}$			$T_{amb} = -40\text{ °C to }+125\text{ °C}$			Unit
			Min	Typ ^[1]	Max	Min	Max (85 °C)	Max (125 °C)	
t_{en}	enable time	$\bar{E}$, Sn to Z or Yn; see Figure 15							
		$V_{CC} = 1.4\text{ V to }1.6\text{ V}$	-	45	100	-	120	125	ns
		$V_{CC} = 1.65\text{ V to }1.95\text{ V}$	-	32	75	-	85	95	ns
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$	-	21	50	-	55	60	ns
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$	-	19	45	-	45	50	ns
		$V_{CC} = 3.6\text{ V to }4.3\text{ V}$	-	19	45	-	45	50	ns
t_{dis}	disable time	$\bar{E}$, Sn to Z or Yn; see Figure 15							
		$V_{CC} = 1.4\text{ V to }1.6\text{ V}$	-	25	80	-	90	105	ns
		$V_{CC} = 1.65\text{ V to }1.95\text{ V}$	-	15	65	-	70	75	ns
		$V_{CC} = 2.3\text{ V to }2.7\text{ V}$	-	9	30	-	35	40	ns
		$V_{CC} = 2.7\text{ V to }3.6\text{ V}$	-	8	25	-	30	35	ns
		$V_{CC} = 3.6\text{ V to }4.3\text{ V}$	-	8	25	-	30	35	ns

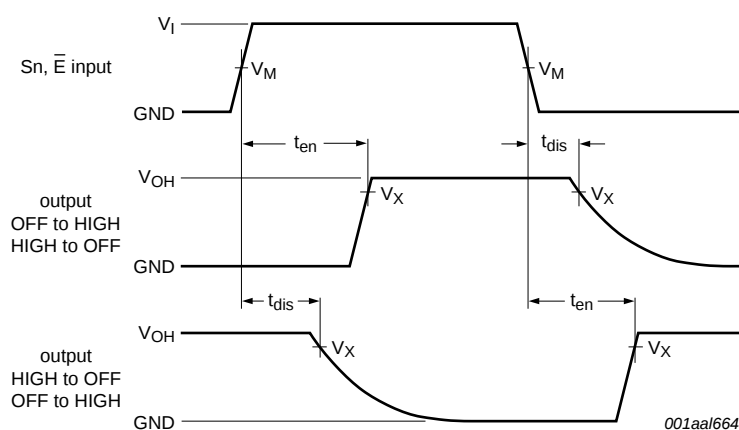
Table 9. Dynamic characteristics ...continuedAt recommended operating conditions; voltages are referenced to GND (ground = 0 V); for load circuit see [Figure 17](#).

Symbol	Parameter	Conditions	T _{amb} = 25 °C			T _{amb} = -40 °C to +125 °C			Unit
			Min	Typ ^[1]	Max	Min	Max (85 °C)	Max (125 °C)	
t _{b-m}	break-before-make time	see Figure 16 ^[2]							
		V _{CC} = 1.4 V to 1.6 V	-	19	-	9	-	-	ns
		V _{CC} = 1.65 V to 1.95 V	-	17	-	7	-	-	ns
		V _{CC} = 2.3 V to 2.7 V	-	12	-	4	-	-	ns
		V _{CC} = 2.7 V to 3.6 V	-	10	-	3	-	-	ns
		V _{CC} = 3.6 V to 4.3 V	-	9	-	2	-	-	ns

[1] Typical values are measured at T_{amb} = 25 °C and V_{CC} = 1.5 V, 1.8 V, 2.5 V, 3.3 V and 4.3 V respectively.

[2] Break-before-make guaranteed by design.

12.1 Waveform and test circuits

Measurement points are given in [Table 10](#).Logic level: V_{OH} is typical output voltage level that occurs with the output load.**Fig 15. Enable and disable times****Table 10. Measurement points**

Supply voltage	Input	Output
V _{CC}	V _M	V _X
1.4 V to 4.3 V	0.5V _{CC}	0.9V _{OH}

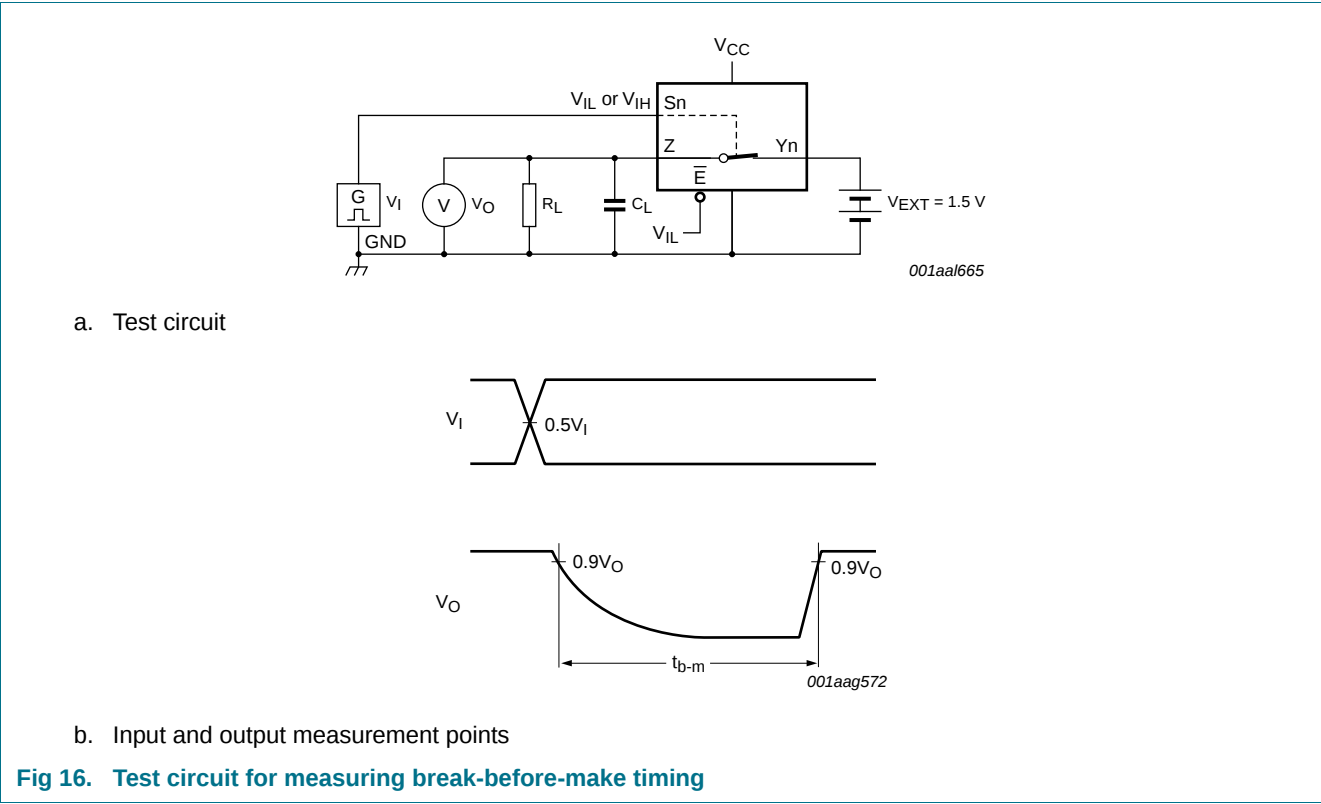


Fig 16. Test circuit for measuring break-before-make timing

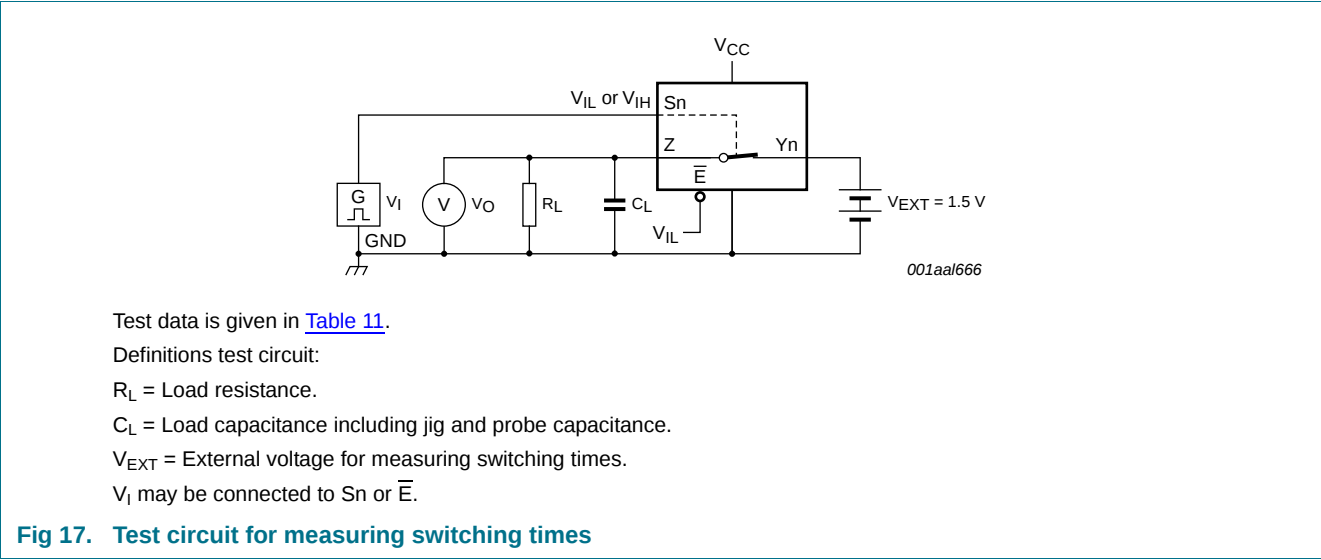


Fig 17. Test circuit for measuring switching times

Table 11. Test data

Supply voltage	Input		Load	
V_{CC}	V_I	t_r, t_f	C_L	R_L
1.4 V to 4.3 V	V_{CC}	$\leq 2.5 \text{ ns}$	35 pF	50 Ω

12.2 Additional dynamic characteristics

Table 12. Additional dynamic characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); $V_I = \text{GND}$ or V_{CC} (unless otherwise specified); $t_r = t_f \leq 2.5 \text{ ns}$; $T_{\text{amb}} = 25 \text{ }^\circ\text{C}$.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
THD	total harmonic distortion	$f_i = 20 \text{ Hz to } 20 \text{ kHz}$; $R_L = 32 \text{ } \Omega$; see Figure 18	[1]			
		$V_{CC} = 1.4 \text{ V}$; $V_I = 1 \text{ V (p-p)}$	-	0.15	-	%
		$V_{CC} = 1.65 \text{ V}$; $V_I = 1.2 \text{ V (p-p)}$	-	0.10	-	%
		$V_{CC} = 2.3 \text{ V}$; $V_I = 1.5 \text{ V (p-p)}$	-	0.02	-	%
		$V_{CC} = 2.7 \text{ V}$; $V_I = 2 \text{ V (p-p)}$	-	0.02	-	%
$f_{(-3\text{dB})}$	–3 dB frequency response	$R_L = 50 \text{ } \Omega$; see Figure 19	[1]			
		$V_{CC} = 1.4 \text{ V to } 4.3 \text{ V}$	-	15	-	MHz
α_{iso}	isolation (OFF-state)	$f_i = 100 \text{ kHz}$; $R_L = 50 \text{ } \Omega$; see Figure 20	[1]			
		$V_{CC} = 1.4 \text{ V to } 4.3 \text{ V}$	-	–90	-	dB
V_{ct}	crosstalk voltage	between digital inputs and switch; $f_i = 1 \text{ MHz}$; $C_L = 50 \text{ pF}$; $R_L = 50 \text{ } \Omega$; see Figure 21				
		$V_{CC} = 1.4 \text{ V to } 3.6 \text{ V}$	-	0.2	-	V
		$V_{CC} = 3.6 \text{ V to } 4.3 \text{ V}$	-	0.3	-	V
Xtalk	crosstalk	between switches; $f_i = 100 \text{ kHz}$; $R_L = 50 \text{ } \Omega$; see Figure 22	[1]			
		$V_{CC} = 1.4 \text{ V to } 4.3 \text{ V}$	-	–90	-	dB
Q_{inj}	charge injection	$f_i = 1 \text{ MHz}$; $C_L = 0.1 \text{ nF}$; $R_L = 1 \text{ M}\Omega$; $V_{\text{gen}} = 0 \text{ V}$; $R_{\text{gen}} = 0 \text{ } \Omega$; see Figure 23				
		$V_{CC} = 1.5 \text{ V}$	-	3	-	pC
		$V_{CC} = 1.8 \text{ V}$	-	4	-	pC
		$V_{CC} = 2.5 \text{ V}$	-	6	-	pC
		$V_{CC} = 3.3 \text{ V}$	-	9	-	pC
		$V_{CC} = 4.3 \text{ V}$	-	15	-	pC

[1] f_i is biased at $0.5V_{CC}$.

12.3 Test circuits

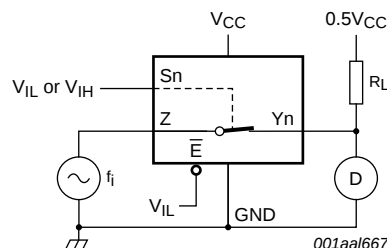
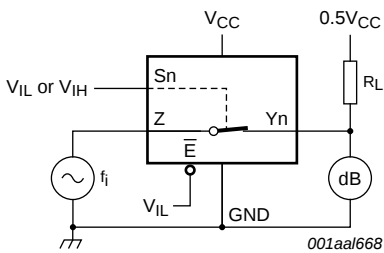
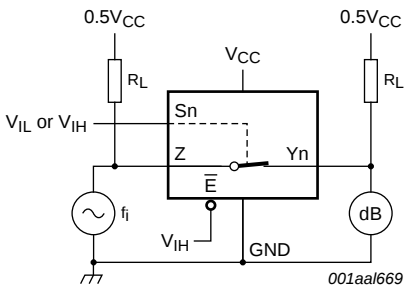


Fig 18. Test circuit for measuring total harmonic distortion



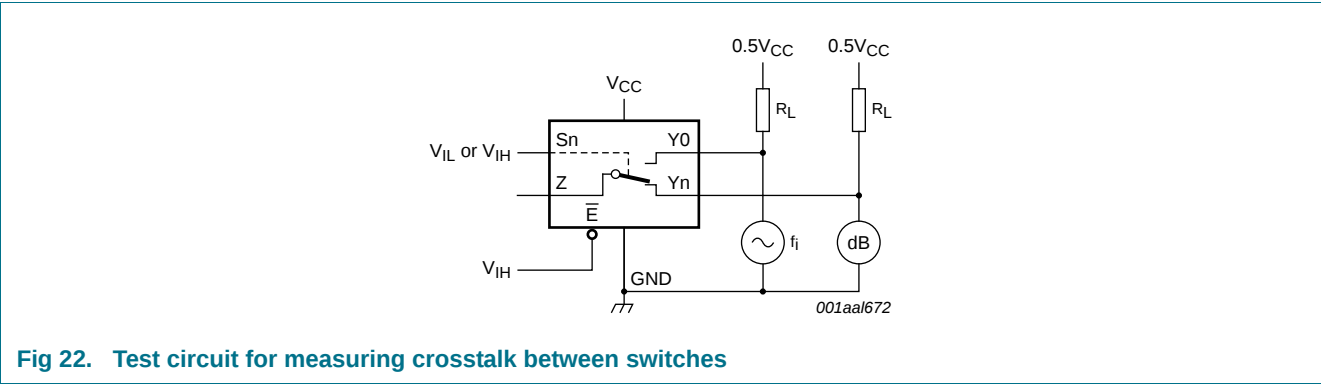
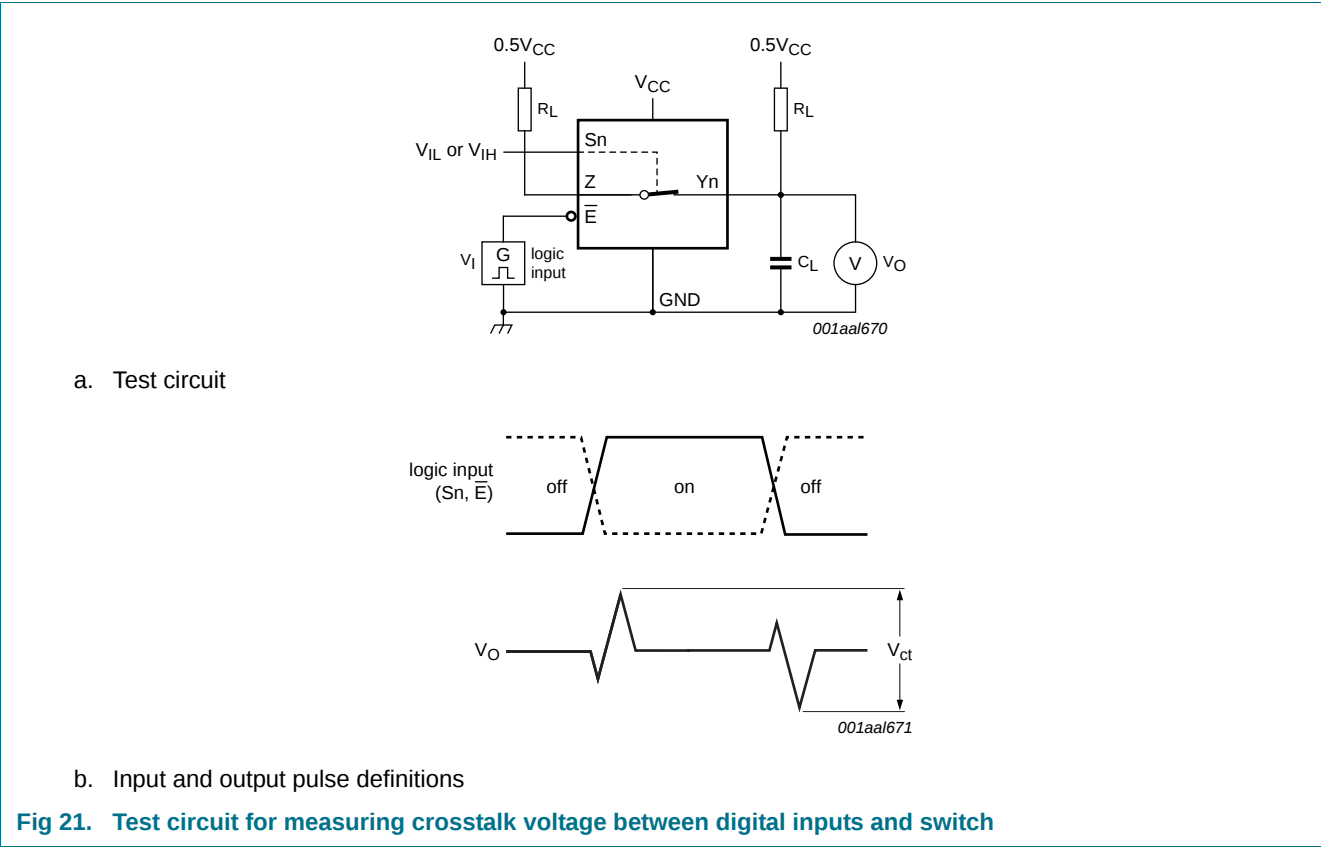
Adjust f_i voltage to obtain 0 dBm level at output. Increase f_i frequency until dB meter reads -3 dB.

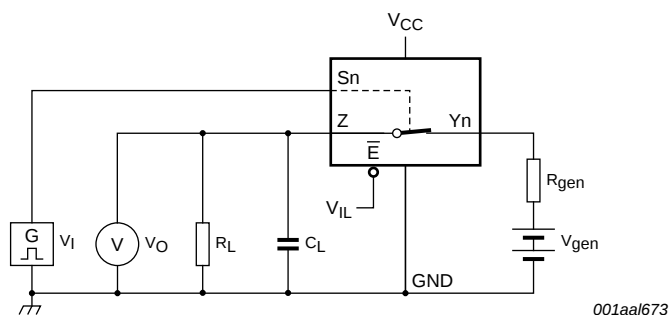
Fig 19. Test circuit for measuring the frequency response when channel is in ON-state



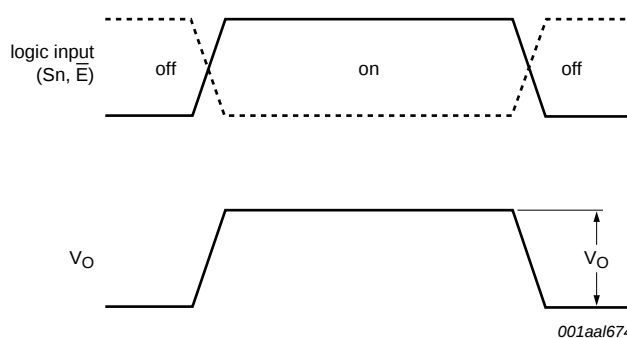
Adjust f_i voltage to obtain 0 dBm level at input.

Fig 20. Test circuit for measuring isolation (OFF-state)





a. Test circuit



b. Input and output pulse definitions

Definition: $Q_{inj} = \Delta V_O \times C_L$.

ΔV_O = output voltage variation.

R_{gen} = generator resistance.

V_{gen} = generator voltage.

V_I may be connected to Sn or $\bar{E}$.

Fig 23. Test circuit for measuring charge injection

13. Package outline

HXQFN16: plastic thermal enhanced extremely thin quad flat package; no leads;
 16 terminals; body 3 x 3 x 0.5 mm
 SOT1039-2

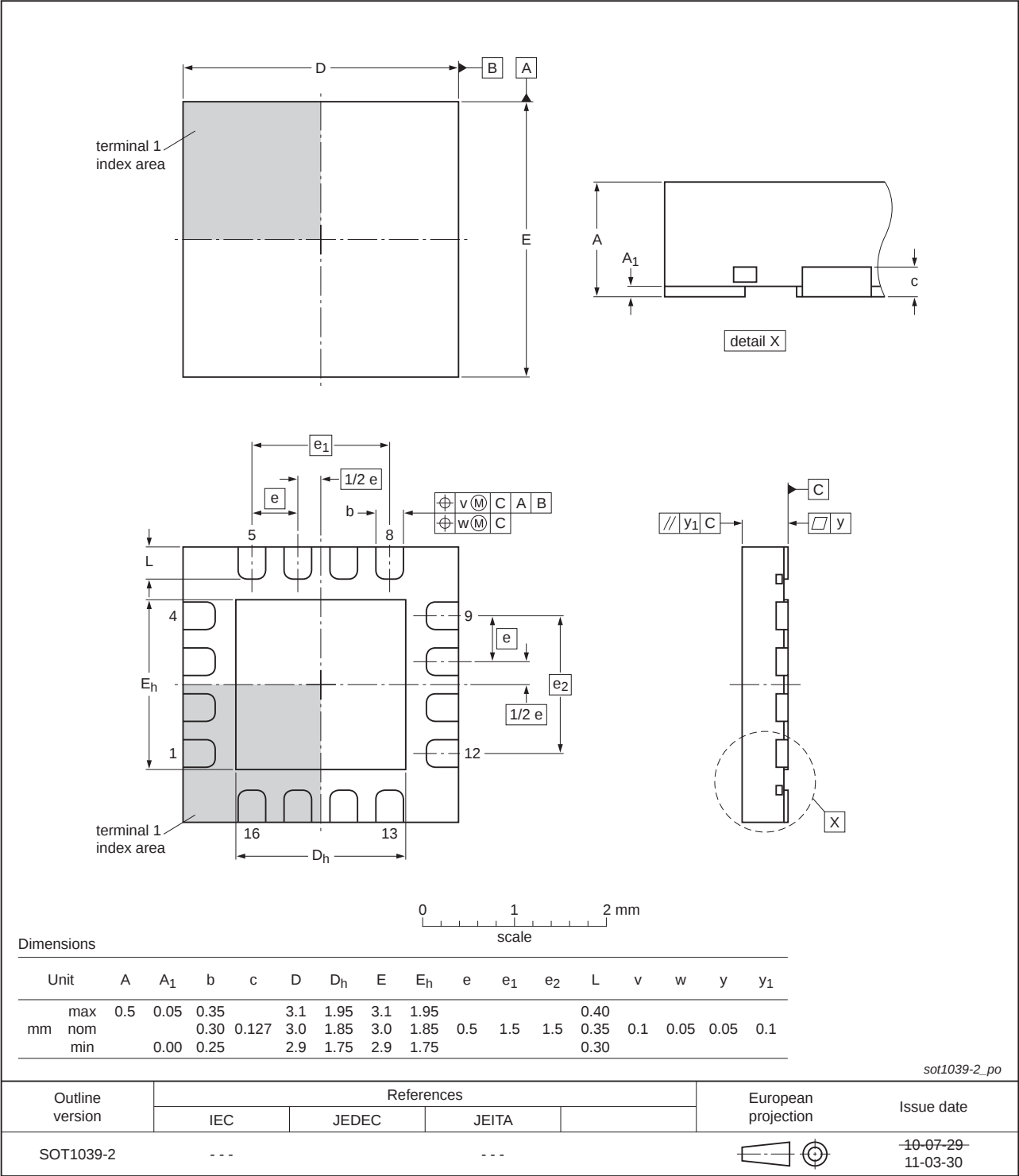


Fig 24. Package outline SOT1039-2 (HXQFN16)

TSSOP16: plastic thin shrink small outline package; 16 leads; body width 4.4 mm

SOT403-1

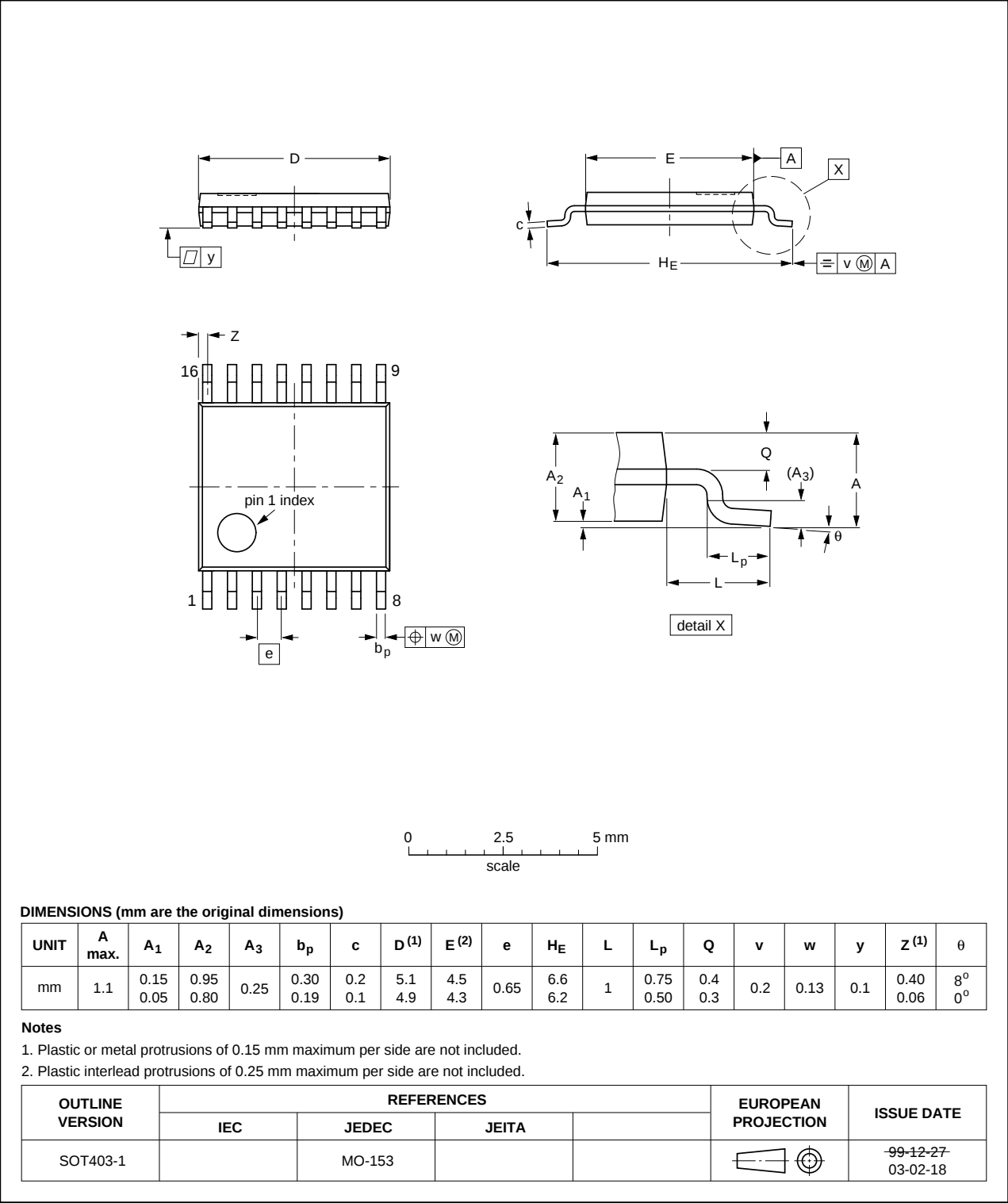


Fig 25. Package outline SOT403-1 (TSSOP16)

14. Abbreviations

Table 13. Abbreviations

Acronym	Description
CDM	Charged Device Model
CMOS	Complementary Metal-Oxide Semiconductor
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
PDA	Personal Digital Assistant
MIL	Military

15. Revision history

Table 14. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
NX3L4051_Q100 v.1	20120807	Product data sheet	-	-

16. Legal information

16.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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Date of release: 7 August 2012

Document identifier: NX3L4051_Q100